Search Notes				

Application/Control	No. Applicant(s)/Patent und Reexamination	er
10/749,456	KIM ET AL.	
Examiner	Art Unit	
Khai M. Nouven	2617	

	SEAR	CHED	
Class	Subclass	Date	Examiner
455	435.3 435.2 435.1 422.1 437 436 434	6/1/2006	KN
455	432.1 407	6/7/2006	KN
455	432.3 406	6/7/2006	KN

INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
attached	6/1/2006	kn	
	Subclass	Subclass Date	

SEARCH (INCLUDING SEAF)
	DATE	EXMR
East (see attached)	6/1/2006	kn
Nick Corsaro	6/7/2006	KN
East (see attached)	6/8/2006	kn